



US00D345704S

United States Patent [19]

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Shirai

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[54] **MULTIMETER**

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4,283,677 11/1981 Niwa D10/79 X

[75] Inventor: **Etsuo Shirai, Ueda, Japan**

FOREIGN PATENT DOCUMENTS

[73] Assignee: **Kaise Kabushiki Kaisha, Nagano, Japan**

61-30771 2/1986 Japan .

[**] Term: **14 Years**

Primary Examiner—Alan P. Douglas
Assistant Examiner—Antoine O. Davis
Attorney, Agent, or Firm—Jordan and Hamburg

[21] Appl. No.: **904,101**

[22] Filed: **Jun. 24, 1992**

[57] CLAIM

[30] Foreign Application Priority Data

The ornamental design for a multimeter, as shown and described.

Jan. 14, 1992 [JP] Japan 4-587

[52] U.S. Cl. **D10/79**

DESCRIPTION

[58] Field of Search 324/72.5, 73 R, 127,
324/129, 133, 149, 156, 126, 128, 130, 158 P,
158 F; D10/79

FIG. 1 is a perspective view of a multimeter showing my new design;

FIG. 2 is a front elevational view thereof;

FIG. 3 is a rear elevational view thereof;

FIG. 4 is a right side elevational view thereof;

FIG. 5 is a left side elevational view thereof;

FIG. 6 is a top plan view thereof;

FIG. 7 is a bottom plan view thereof; and,

FIG. 8 is a front elevational view indicating a clamp-open status.

[56] References Cited

U.S. PATENT DOCUMENTS

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D. 219,273 11/1970 Shimasaki D10/79
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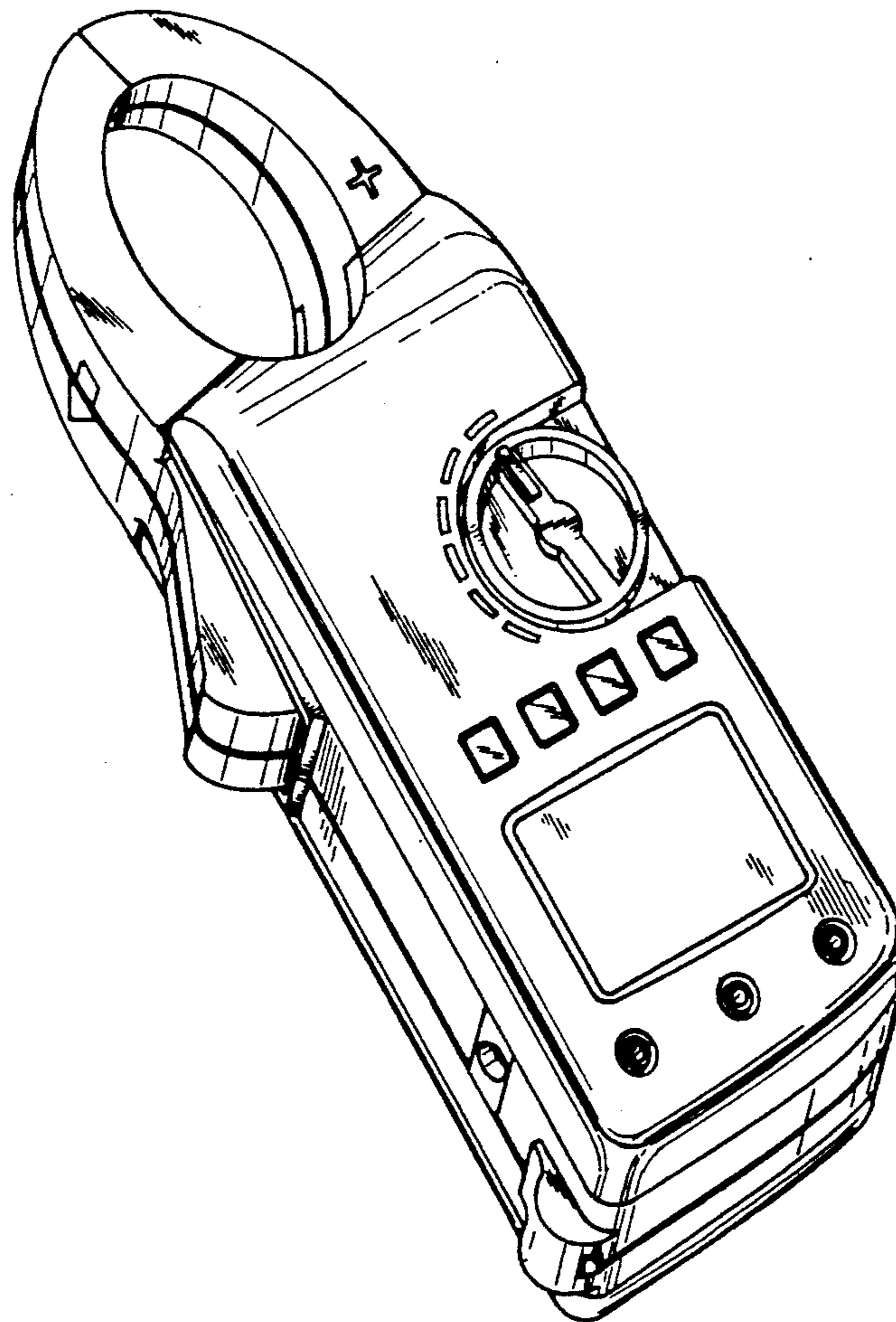


FIG. 1

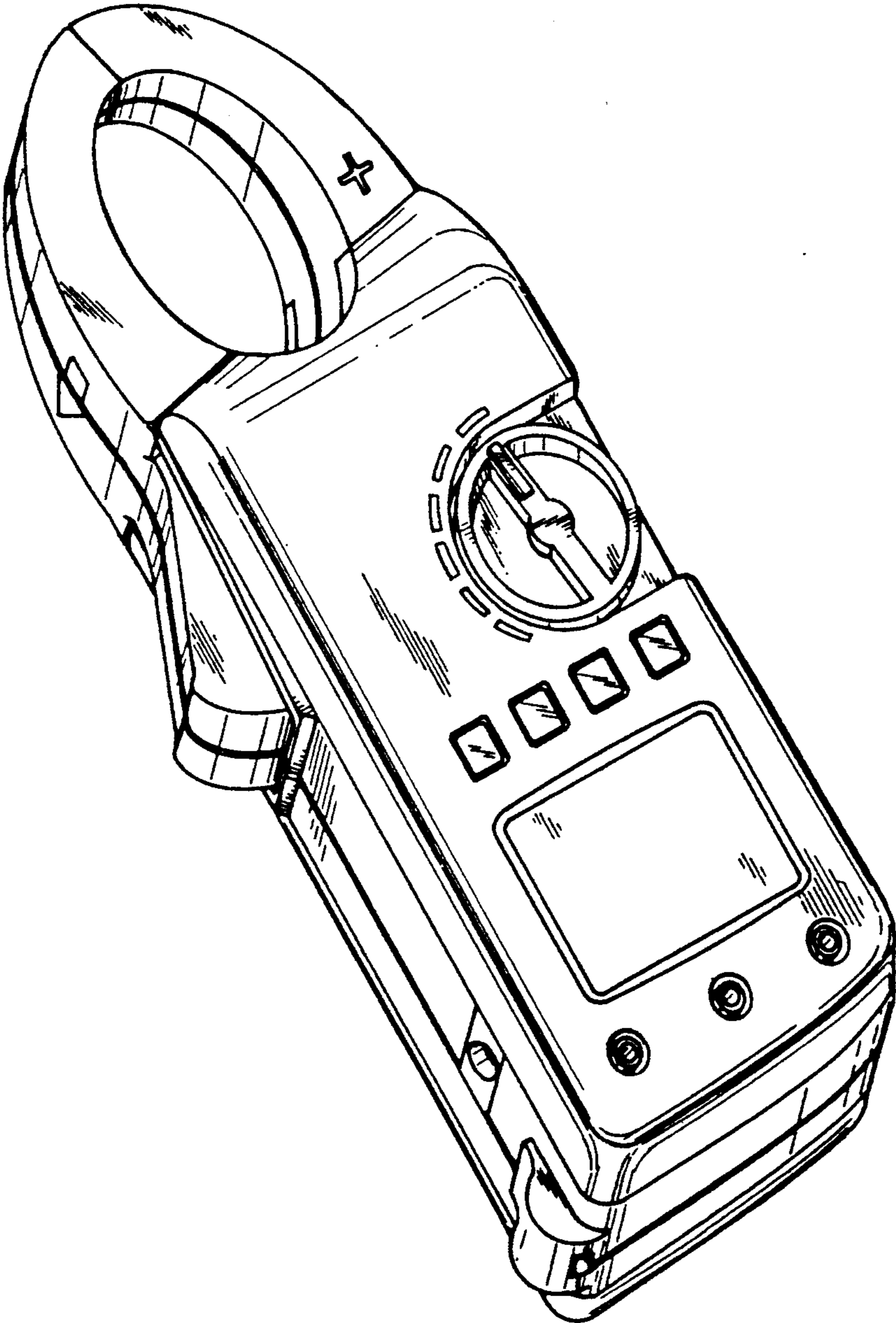


FIG. 2

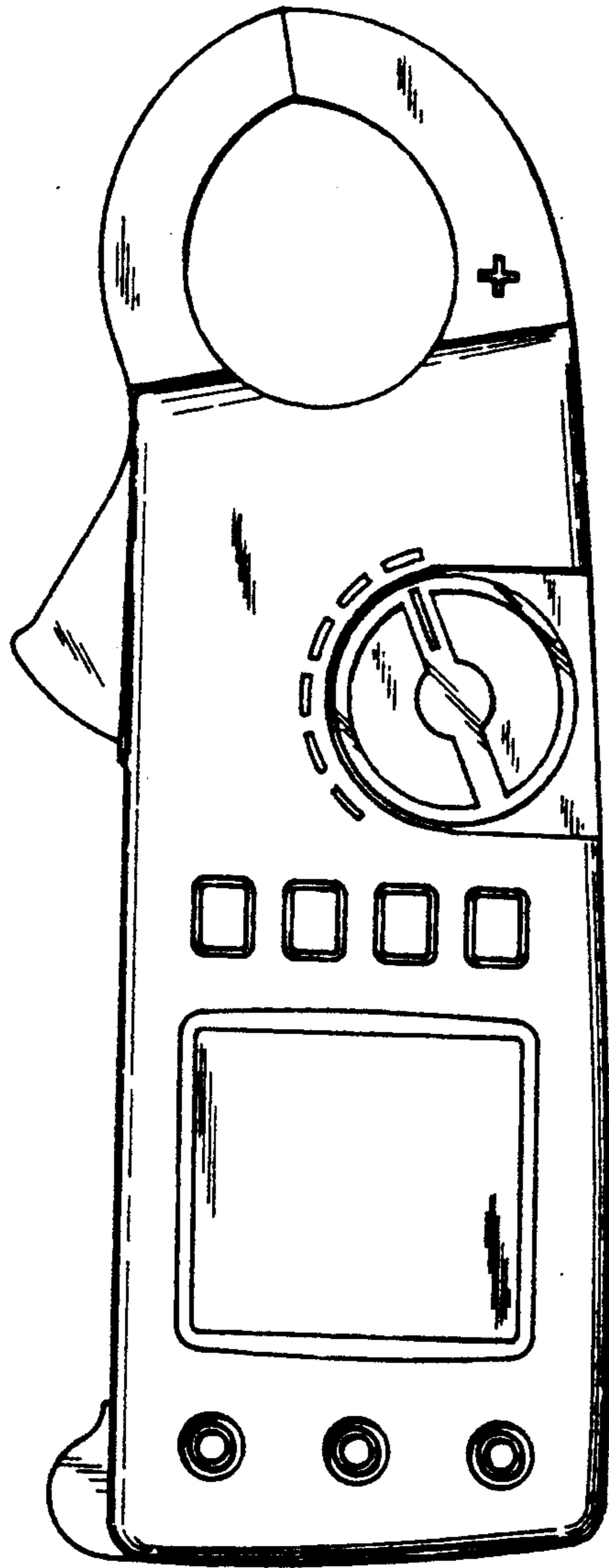


FIG. 3

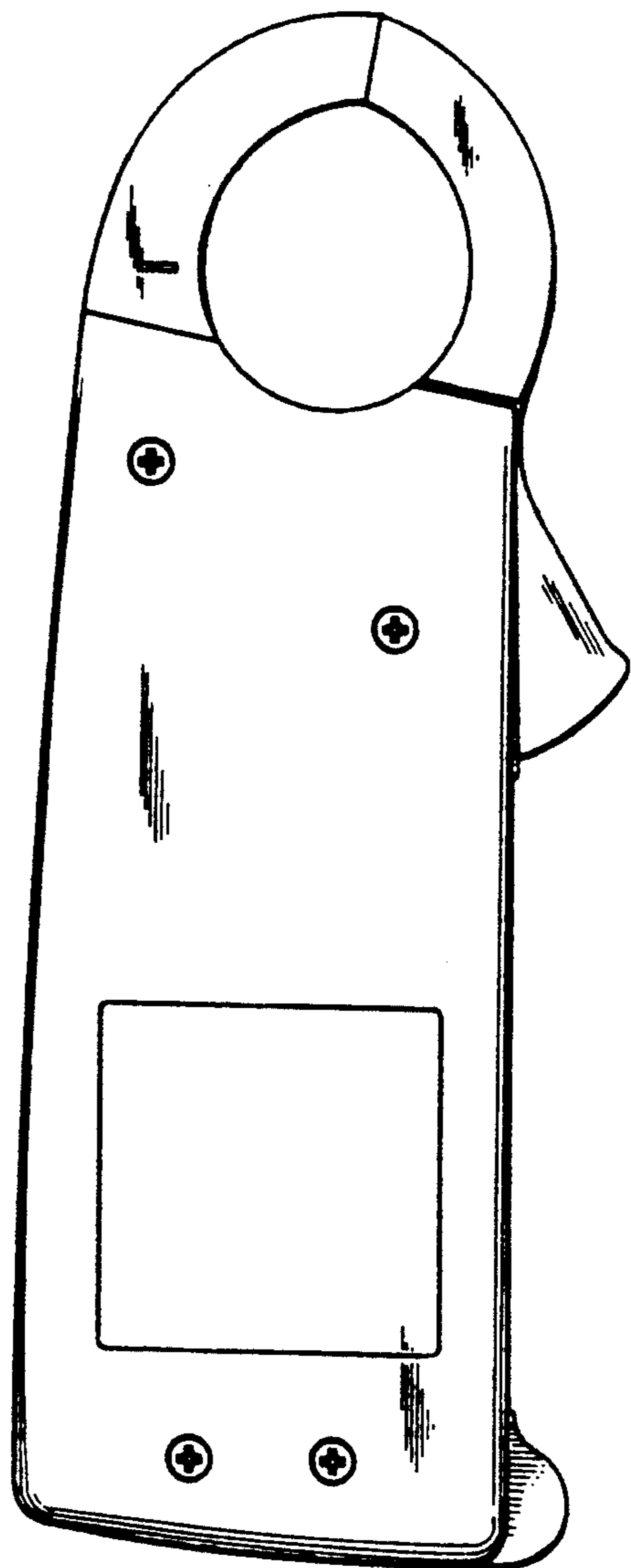


FIG. 4

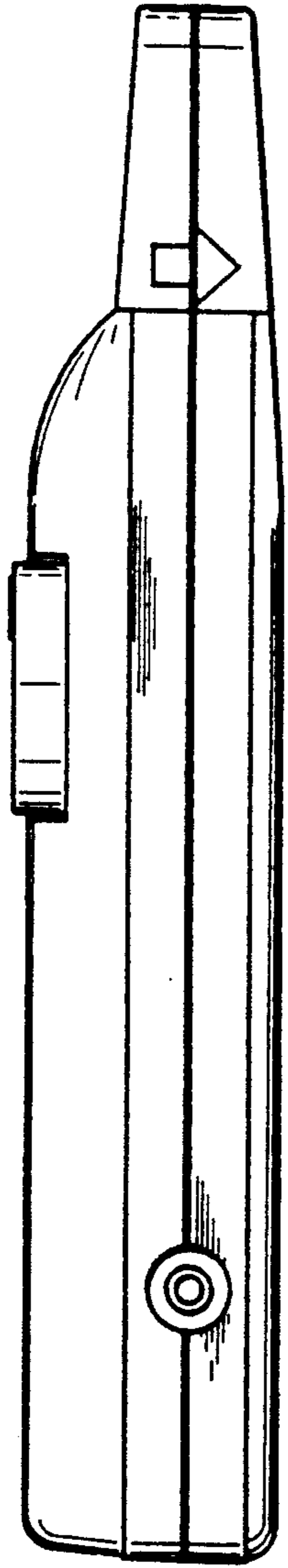


FIG. 5



FIG. 6

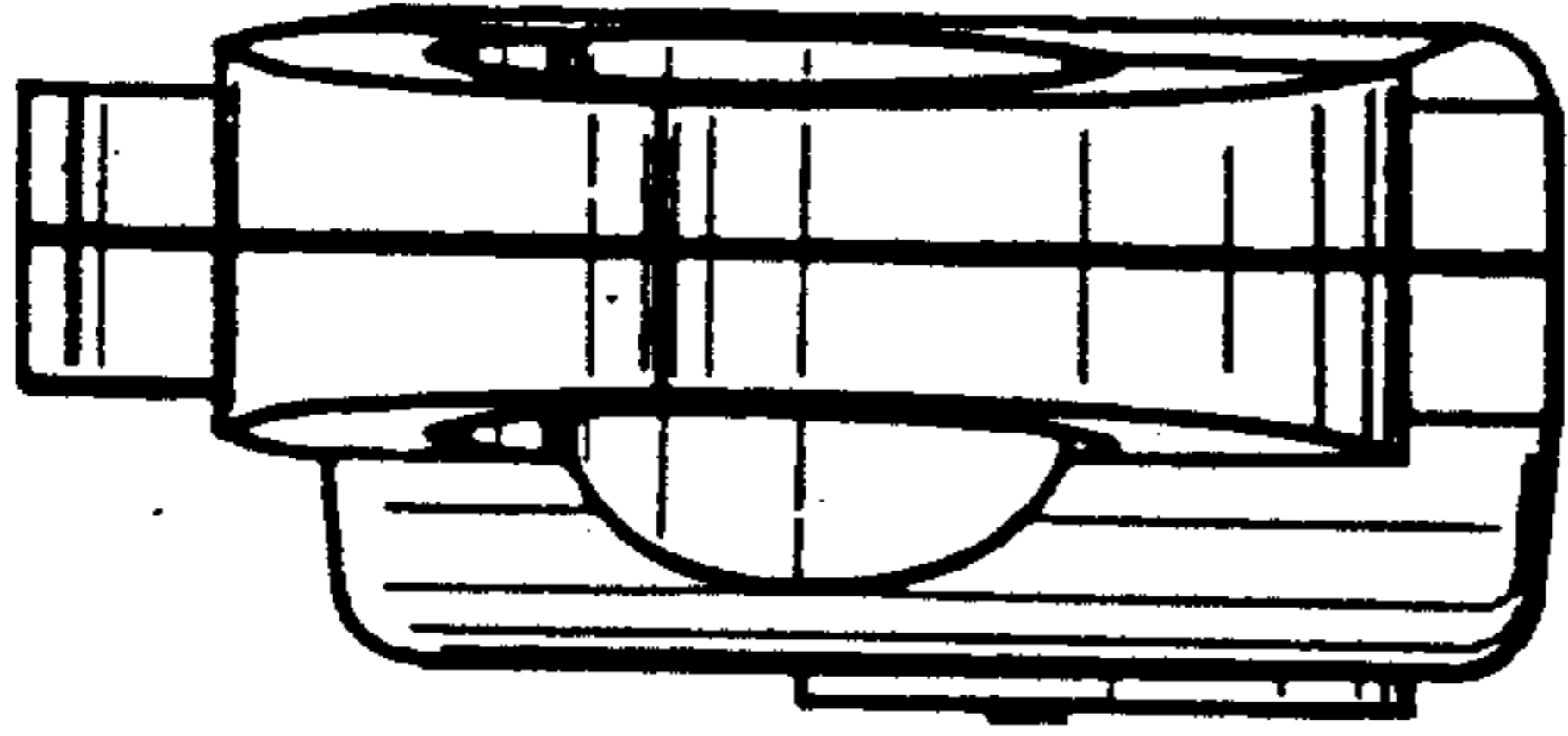


FIG. 7

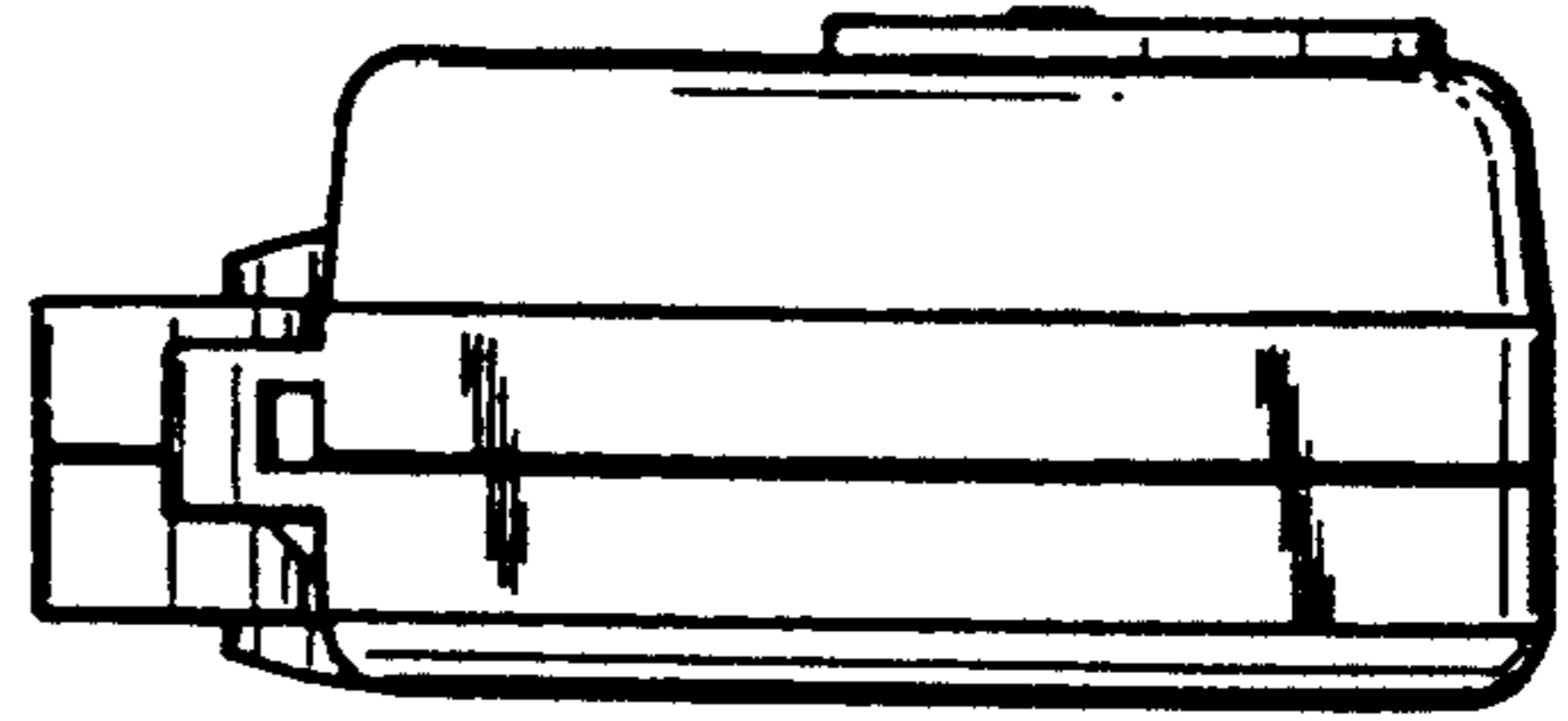


FIG. 8

